

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ISHIDA ET AL.	
		Examiner Qutub Ghulamali	Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,922,452 B2	07-2005	Sandberg, David	375/346
*	B	US-6,882,680 B1	04-2005	Oleynik, Vladislav A.	375/147
*	C	US-5,402,443 A	03-1995	Wong, Hee	375/226
*	D	US-6,263,034 B1	07-2001	Kanack et al.	375/371
*	E	US-4,654,861	03-1987	Godard, Dominique	375/226
*	F	US-6,661,836 B1	12-2003	Dalal et al.	375/226
*	G	US-5,757,652 A	05-1998	Blazo et al.	702/69
*	H	US-6,442,214 B1	08-2002	Boleskei et al.	375/299
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Voorakaranam et al "Low-cost Jitter Measurement Technique for Phase-Locked Loop", (Proceedings of the 43rd IEEE Midwest Symposium on Circuits and Systems, 2000).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.